

Process Fallout

Calculated Capability Ratio	<i>Cp</i> Fallout (both sides combined)	<i>Cpk</i> Fallout (one side only)
0.50	133,620	66,810
0.60	71,860	35,930
0.70	35,720	17,860
0.80	16,400	8,200
0.90	6,940	3,470
1.00	2,700	1,350
1.10	966	483
1.20	318	159
1.30	96	48
1.40	26	13
1.50	7	3
1.60	2	0.800
1.70	0.340	0.170
1.80	0.060	0.030
1.90	0.012	0.006
2.00	0.002	0.001

Fallout rates expressed in PPM (Parts Per Million)

Control Chart Constants

Xbar and R Control Charts					Xbar and S Control Charts				
n	A ₂	D ₃	D ₄	D ₂	n	A ₃	B ₃	B ₄	C ₄
1	2.660	0	3.265	1.128	10	0.975	0.248	1.715	0.9727
2	1.880	0	3.265	1.128	11	0.927	0.321	1.679	0.9754
3	1.023	0	2.574	1.693	12	0.886	0.354	1.646	0.9776
4	0.729	0	2.282	2.059	13	0.850	0.382	1.618	0.9794
5	0.577	0	2.114	2.326	14	0.817	0.406	1.594	0.9810
6	0.483	0	2.004	2.534	15	0.789	0.428	1.582	0.9823
7	0.419	0.076	1.924	2.704	16	0.763	0.448	1.552	0.9835
8	0.373	0.136	1.864	2.847	17	0.739	0.466	1.534	0.9845
9	0.337	0.184	1.816	2.970	18	0.718	0.482	1.518	0.9854
10	0.308	0.223	1.777	3.078	19	0.698	0.497	1.503	0.9862
11	0.285	0.256	1.744	3.173	20	0.680	0.510	1.160	0.9869
12	0.266	0.283	1.717	3.258	21	0.663	0.523	1.477	0.9876
					22	0.647	0.524	1.133	0.9882
					23	0.633	0.545	1.455	0.9887
					24	0.619	0.555	1.445	0.9892
					25	0.606	0.565	1.435	0.9896

Control Chart Formulas

Variable Data Control Charts

Plot Points	Centerline	Control Limits	$\hat{\sigma}$
Std.	Target		
\bar{X}	\bar{X} - Tar	$\bar{\bar{X}} = \frac{\sum \bar{X}}{k}$	$UCL_{\bar{X}} = \bar{\bar{X}} + A_2 \bar{R}$ $LCL_{\bar{X}} = \bar{\bar{X}} - A_2 \bar{R}$
R	R	$\bar{R} = \frac{\sum R}{k}$	$UCL_R = D_4 \bar{R}$ $LCL_R = D_3 \bar{R}$
IX	IX-Tar	$\bar{IX} = \frac{\sum IX}{k}$	$UCL_{IX} = \bar{IX} + A_2 \bar{MR}$ $LCL_{IX} = \bar{IX} - A_2 \bar{MR}$
MR	MR	$\bar{MR} = \frac{\sum MR}{k-I}$	$UCL_{MR} = D_4 \bar{MR}$ $LCL_{MR} = 0$
S	S	$\bar{s} = \frac{\sum s}{k}$	$UCL_s = B_4 \bar{s}$ $LCL_s = B_3 \bar{s}$

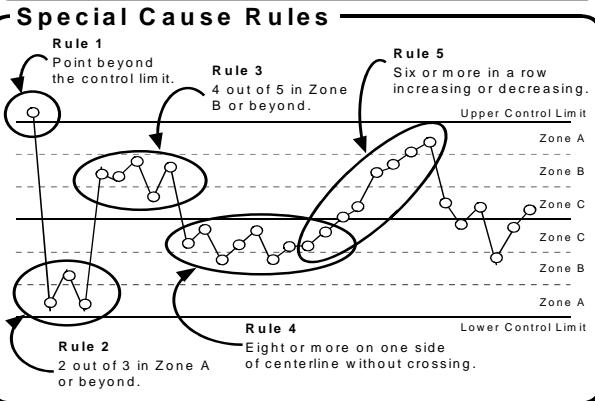
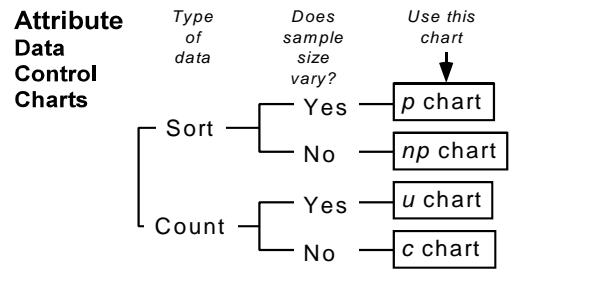
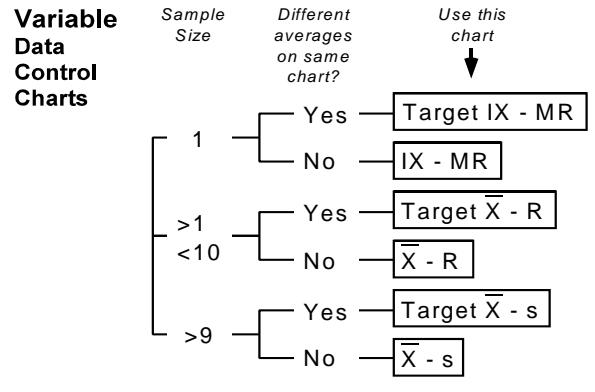
Attribute Data Control Charts

Chart	Plot Point	Centerline	Control Limits	$\hat{\sigma}$
p	p	$\bar{p} = \frac{\sum p}{k}$	$UCL_p = \bar{p} + 3\sqrt{\frac{\bar{p}(1-\bar{p})}{n}}$ $LCL_p = \bar{p} - 3\sqrt{\frac{\bar{p}(1-\bar{p})}{n}}$	$\sqrt{\frac{\bar{p}(1-\bar{p})}{n}}$
np	np	$n\bar{p} = \frac{\sum np}{k}$	$UCL_{np} = D_4 \bar{R}$ $LCL_{np} = D_3 \bar{R}$	$\sqrt{n\bar{p}(1-n\bar{p})}$
c	c	$\bar{c} = \frac{\sum c}{k}$	$UCL_{IX} = \bar{IX} + A_2 \bar{MR}$ $LCL_{IX} = \bar{IX} - A_2 \bar{MR}$	$\sqrt{\bar{c}}$
u	u	$\bar{u} = \frac{\sum u}{k}$	$UCL_{MR} = D_4 \bar{MR}$ $LCL_{MR} = 0$	$\sqrt{\frac{\bar{u}}{n}}$

Glossary of Symbols

- A₂ = Control limit constant used for Xbar and IX charts.
- A₃ = Control limit constant used for sigma charts.
- B₃ = Control limit constant used for sigma charts.
- B₄ = Control limit constant used for sigma charts.
- C = Number of defects. Plot point on c chart.
- C₄ = Control limit constant used for sigma charts.
- Cp = Process potential capability ratio.
- Cpk = Process performance capability ratio (lower side).
- Cpk_u = Process performance capability ratio (upper side).
- d₂ = Calculation constant used to estimate process sigma.
- D₃ = Control limit constant used in for Range charts.
- D₄ = Control limit constant used in for Range charts.
- k = Number of subgroups.
- LCL = Lower control limit.
- LSL = Lower specification limit.
- MR = Moving-range.
- n = Number of measurements in a subgroup (sample size).
- np = Number defective. Plot point on an np-chart.
- PPM = Parts per million.
- R = Range.
- s = Sample standard deviation.
- S = Population standard deviation.
- S = Estimated population standard deviation.
- S = Summation of.
- Tar = Desired process centering (e.g., engineering nominal).
- u = Average defects per unit. Plot point on u-chart.
- UCL = Upper control limit.
- USL = Upper specification limit.
- X or IX = Individual measurement.
- X = Average.
- X̄ = Average of averages.

Control Chart Selection Trees

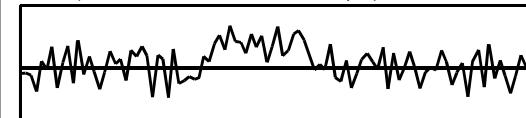


Common Control Chart Patterns

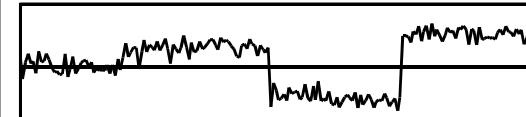
Random Pattern



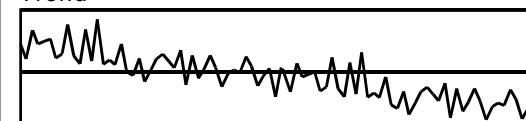
Run (above centerline in this example)



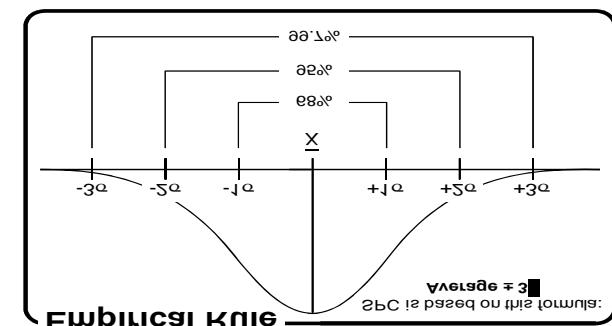
Shift



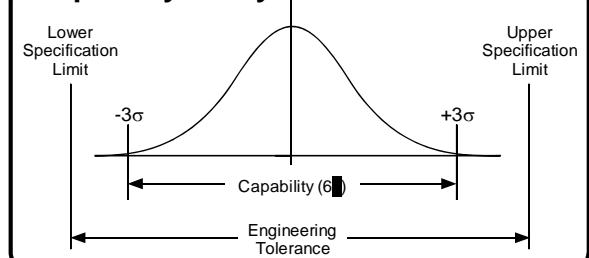
Trend



SPC Tri-Fold Card



Capability Study



Capability Study Formulas

$C_p = \frac{USL - LSL}{6\sigma}$	$\bar{X} = \frac{\sum X}{n}$
$C_{pk_L} = \frac{\bar{X} - LSL}{3\sigma}$	$\sigma = \sqrt{\frac{\sum (X_i - \bar{X})^2}{n-1}}$ (Root mean square method)
$C_{pk_U} = \frac{USL - \bar{X}}{3\sigma}$	$\hat{\sigma} = \frac{\bar{R}}{d_2}$ (Range control chart method)

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